

March 2013

FDB28N30

N-Channel UniFETTM MOSFET 300 V, 28 A, 129 $m\Omega$

Features

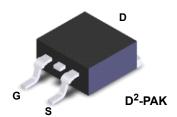
- $R_{DS(on)}$ = 108 m Ω (Typ.) @ V_{GS} = 10 V, I_D = 14 A
- Low Gate Charge (Typ. 39 nC)
- Low Crss (Typ. 35 pF)
- 100% Avalanche Tested
- · RoHS Compliant

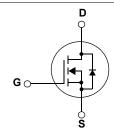
Applications

- · Uninterruptible Power Supply
- · AC-DC Power Supply

Description

UniFETTM MOSFET is Fairchild Semiconductor[®]'s high voltage MOSFET family based on planar stripe and DMOS technology. This MOSFET is tailored to reduce on-state resistance, and to provide better switching performance and higher avalanche energy strength. This device family is suitable for switching power converter applications such as power factor correction (PFC), flat panel display (FPD) TV power, ATX and electronic lamp ballasts.





MOSFET Maximum Ratings T_C = 25°C unless otherwise noted*

| Symbol | | Parameter | | FDB28N30 | Unit |
|-----------------------------------|--|---------------------------------------|-------------------|-------------|------|
| V_{DSS} | Drain to Source Voltage | | | 300 | V |
| V_{GSS} | Gate to Source Voltage | | | ±30 | V |
| | Drain Current | - Continuous (T _C = 25°C) | | 28 | Α |
| 'D | DiamCurrent | - Continuous (T _C = 100°C) | | 19 | A |
| I _{DM} | Drain Current | - Pulsed | - Pulsed (Note 1) | | Α |
| E _{AS} | Single Pulsed Avalanche Energy (Note 2) | | (Note 2) | 588 | mJ |
| I _{AR} | Avalanche Current | | (Note 1) | 28 | Α |
| E _{AR} | Repetitive Avalanche Energy | | (Note 1) | 25 | mJ |
| dv/dt | Peak Diode Recovery dv/dt | | (Note 3) | 4.5 | V/ns |
| Б | Dower Dissipation | (T _C = 25°C) | | 250 | W |
| P_{D} | Power Dissipation | - Derate above 25°C | | 2.0 | W/°C |
| T _J , T _{STG} | Operating and Storage Temperature Range | | | -55 to +150 | °C |
| T_L | Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds | | | 300 | °C |

Thermal Characteristics

| Symbol | Parameter | FDB28N30 | Unit |
|-------------------|---|----------|------|
| $R_{\theta JC}$ | Thermal Resistance, Junction to Case, Max. | 0.5 | |
| $R_{\theta JA}^*$ | Thermal Resistance, Junction to Ambient* | 40 | °C/W |
| $R_{\theta JA}$ | Thermal Resistance, Junction to Ambient, Max. | 62.5 | |

^{*}When mounted on the minimum pad size recommended (PCB Mount)

Package Marking and Ordering Information $T_C = 25^{\circ}C$ unless otherwise noted

| Device Marking | Device | Package | Reel Size | Tape Width | Quantity |
|----------------|------------|---------|-----------|------------|----------|
| FDB28N30 | FDB28N30TM | D2-PAK | 330mm | 24mm | 800 |

Electrical Characteristics

| Symbol | Parameter | Test Conditions | Min. | Тур. | Max. | Unit |
|---|--|--|------|------|------|------|
| Off Charac | cteristics | | | | | |
| BV _{DSS} | Drain to Source Breakdown Voltage | $I_D = 250\mu A$, $V_{GS} = 0V$, $T_J = 25^{\circ}C$ | 300 | - | - | V |
| ΔBV _{DSS} / ΔΤ _J | Breakdown Voltage Temperature Coefficient | I _D = 250μA, Referenced to 25°C | - | 0.4 | - | V/°C |
| 1 | Zoro Coto Voltago Droin Current | V _{DS} = 300V, V _{GS} = 0V | - | - | 1 | |
| IDSS | Zero Gate Voltage Drain Current | $V_{DS} = 240V, T_C = 125^{\circ}C$ | - | - | 10 | μΑ |
| I _{GSS} | Gate to Body Leakage Current | $V_{GS} = \pm 30V, V_{DS} = 0V$ | - | - | ±100 | nA |

On Characteristics

| V _{GS(th)} | Gate Threshold Voltage | $V_{GS} = V_{DS}, I_{D} = 250 \mu A$ | 3.0 | - | 5.0 | V |
|---------------------|--------------------------------------|---|-----|-------|-------|---|
| R _{DS(on)} | Static Drain to Source On Resistance | V _{GS} = 10V, I _D = 14A | - | 0.108 | 0.129 | Ω |
| 9 _{FS} | Forward Transconductance | $V_{DS} = 40V, I_{D} = 14A$ | ı | 24.8 | - | S |

Dynamic Characteristics

| C _{iss} | Input Capacitance | \\ - 25\\ \\ - 20\\ | - | 1690 | 2250 | pF |
|------------------|-------------------------------|---|---|------|------|----|
| C _{oss} | Output Capacitance | $V_{DS} = 25V, V_{GS} = 0V$ f = 1MHz | | 305 | 405 | pF |
| C _{rss} | Reverse Transfer Capacitance | T - TWITZ | - | 35 | 50 | pF |
| Q_g | Total Gate Charge at 10V | | - | 39 | 50 | nC |
| Q_{gs} | Gate to Source Gate Charge | $V_{DS} = 240V, I_{D} = 28A$ | - | 12 | - | nC |
| Q _{gd} | Gate to Drain "Miller" Charge | V _{GS} = 10V (Note 4) | - | 17 | - | nC |

Switching Characteristics

| t _{d(on)} | Turn-On Delay Time | | | - | 35 | 80 | ns |
|---------------------|---------------------|--|----------|---|-----|-----|----|
| t _r | Turn-On Rise Time | V _{DD} = 150V, I _D = 28A | | - | 135 | 280 | ns |
| t _{d(off)} | Turn-Off Delay Time | $R_G = 25\Omega$ | | - | 79 | 168 | ns |
| t _f | Turn-Off Fall Time | | (Note 4) | - | 69 | 148 | ns |

Drain-Source Diode Characteristics

| I_S | Maximum Continuous Drain to Source Diode Forward Current | | - | - | 28 | Α |
|-----------------|--|---|---|-----|-----|----|
| I _{SM} | Maximum Pulsed Drain to Source Diode Forward Current | | - | - | 112 | Α |
| V_{SD} | Drain to Source Diode Forward Voltage | V _{GS} = 0V, I _{SD} = 28A | - | - | 1.4 | V |
| t _{rr} | Reverse Recovery Time | V _{GS} = 0V, I _{SD} = 28A | - | 279 | - | ns |
| Q_{rr} | Reverse Recovery Charge | $dI_F/dt = 100A/\mu s$ | - | 2.7 | - | μС |

Notes

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature
- 2. L = 1.5mH, I_{AS} = 28A, V_{DD} = 50V, R_{G} = 25 Ω , Starting T_{J} = 25 $^{\circ}$ C
- 3. $I_{SD} \le 28 A$, di/dt $\le 200 A/\mu s$, $V_{DD} \le BV_{DSS}$, Starting T_J = $25^{\circ}C$
- 4. Essentially Independent of Operating Temperature Typical Characteristics

Typical Performance Characteristics

Figure 1. On-Region Characteristics

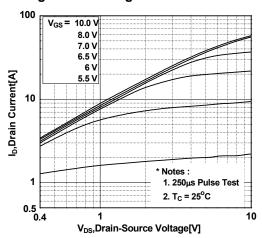


Figure 3. On-Resistance Variation vs.
Drain Current and Gate Voltage

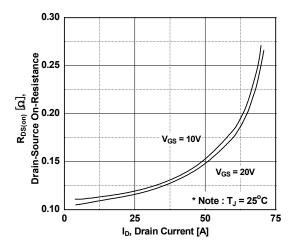


Figure 5. Capacitance Characteristics

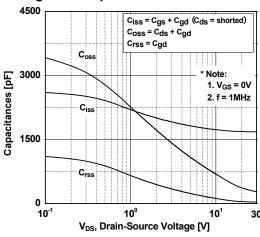


Figure 2. Transfer Characteristics

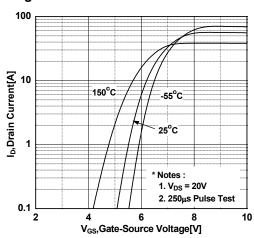


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

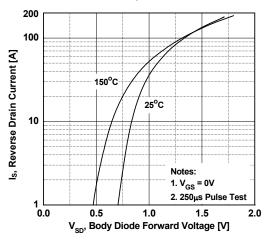
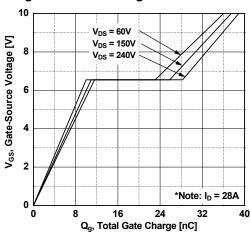


Figure 6. Gate Charge Characteristics



Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

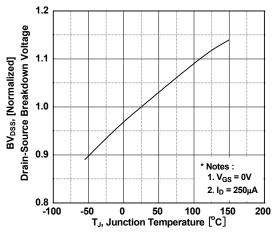


Figure 8. On-Resistance Variation vs. Temperature

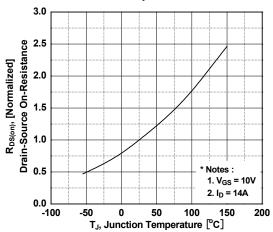


Figure 9. Maximum Safe Operating Area

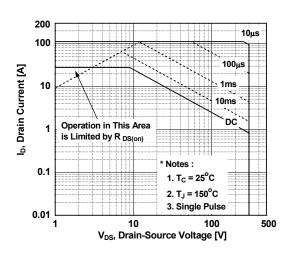


Figure 10. Maximum Drain Current vs. Case Temperature

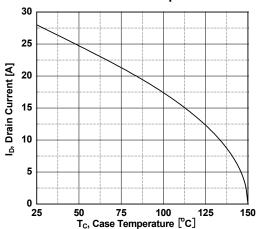
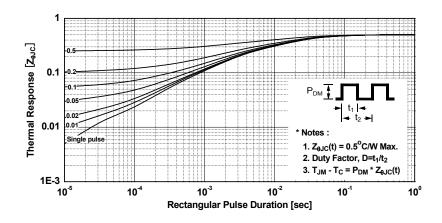
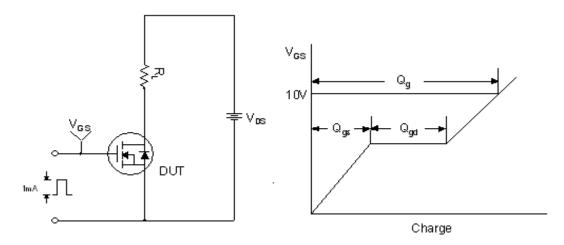


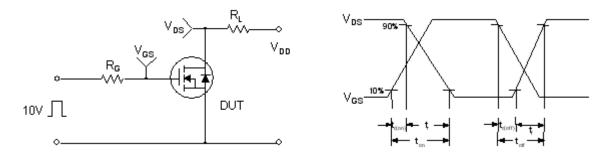
Figure 11. Transient Thermal Response Curve



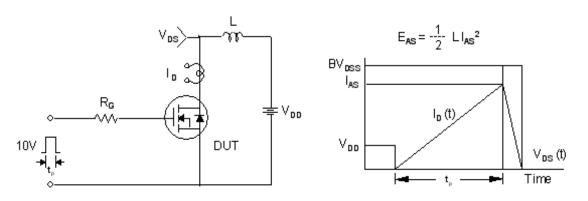
Gate Charge Test Circuit & Waveform



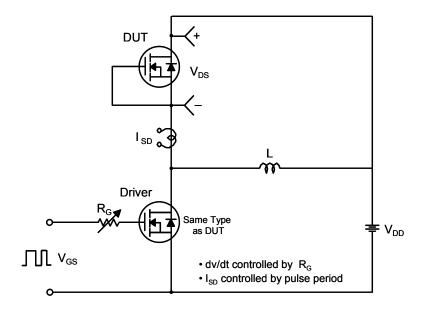
Resistive Switching Test Circuit & Waveforms

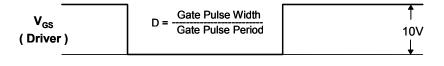


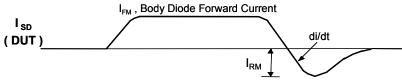
Unclamped Inductive Switching Test Circuit & Waveforms



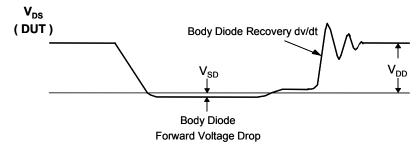
Peak Diode Recovery dv/dt Test Circuit & Waveforms





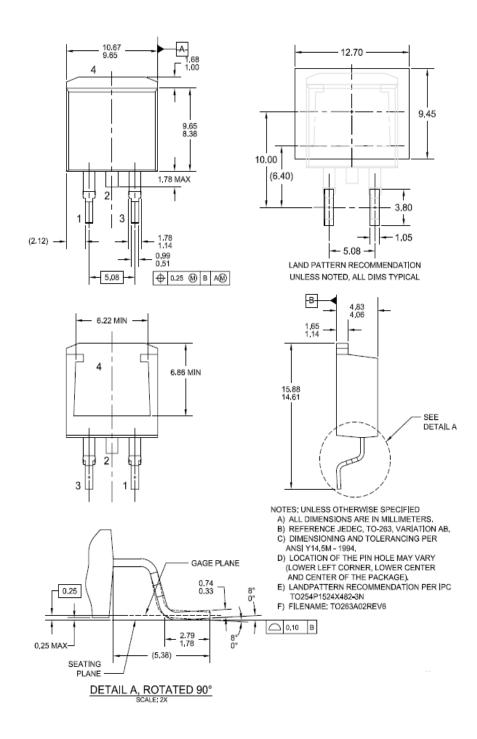


Body Diode Reverse Current



Mechanical Dimensions

D²PAK







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